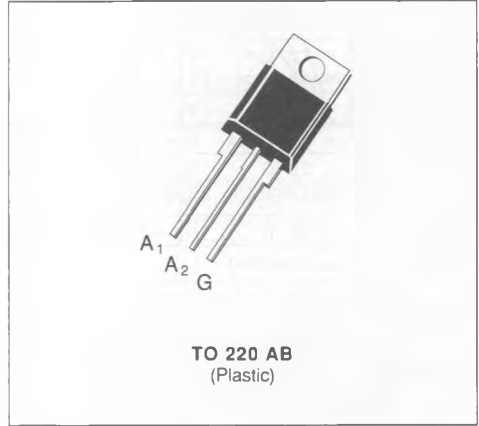




TRIACS

- GLASS PASSIVATED CHIP
- I<sub>G</sub>T SPECIFIED IN FOUR QUADRANTS



**DESCRIPTION**

New range suited for applications such as phase control and static switching.

**ABSOLUTE RATINGS** (limiting values)

Symbol	Parameter	Value	Unit
I <sub>T(RMS)</sub>	RMS on-state Current (360° conduction angle) T <sub>C</sub> = 90 °C	15	A
I <sub>TSM</sub>	Non Repetitive Surge Peak on-state Current (T <sub>J</sub> initial = 25 °C - Half sine wave)	t = 8.3 ms	157
		t = 10 ms	150
I <sup>2</sup> t	I <sup>2</sup> t Value for Fusing t = 10 ms	112.5	A <sup>2</sup> s
di/dt	Critical Rate of Rise of on-state Current (1)	Repetitive F = 50 Hz	10
		Non Repetitive	50
T <sub>stg</sub> T <sub>J</sub>	Storage and Operating Junction Temperature Range	- 40 to 150 - 40 to 125	°C °C

Symbol	Parameter	BTB 15-					Unit
		200B	400B	600B	700B	800B	
V <sub>DRM</sub>	Repetitive Peak off-state Voltage (2)	200	400	600	700	800	V

(1) I<sub>G</sub> = 750 mA    di<sub>C</sub>/dt = 1 A/μs  
(2) T<sub>J</sub> = 125 °C.

**THERMAL RESISTANCES**

Symbol	Parameter	Value	Unit
R <sub>th(j-a)</sub>	Junction to Ambient	60	°C/W
R <sub>th(j-c) DC</sub>	Junction to Case for DC	2.66	°C/W
R <sub>th(j-c) AC</sub>	Junction to Case for 360° Conduction Angle (F = 50 Hz)	2	°C/W

**GATE CHARACTERISTICS** (maximum values)

$P_{GM} = 40 \text{ W}$  ( $t_p = 10 \mu\text{s}$ )       $I_{GM} = 4 \text{ A}$  ( $t_p = 10 \mu\text{s}$ )  
 $P_{G(AV)} = 1 \text{ W}$        $V_{GM} = 16 \text{ V}$  ( $t_p = 10 \mu\text{s}$ )

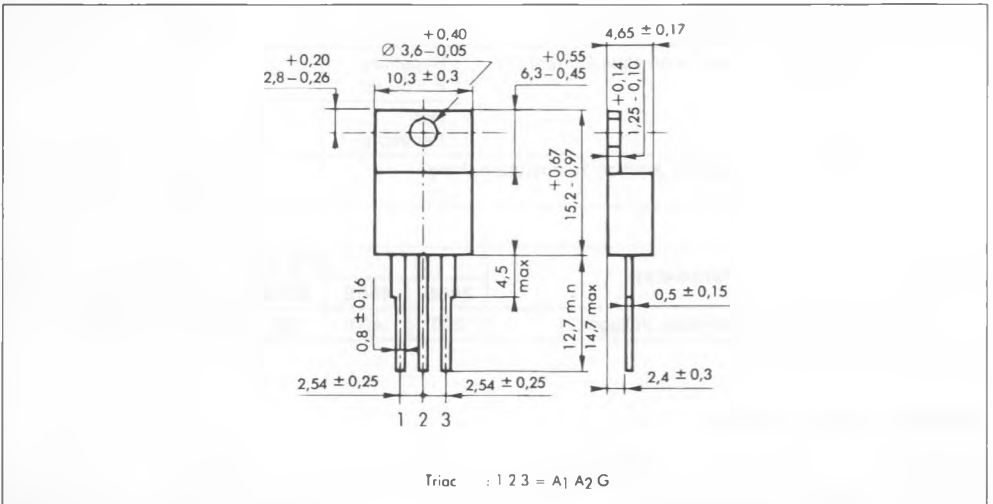
**ELECTRICAL CHARACTERISTICS**

Symbol	Test Conditions			Quadrants	Min.	Typ.	Max.	Unit
$I_{GT}$	$T_j = 25 \text{ }^\circ\text{C}$ Pulse Duration $> 20 \mu\text{s}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III			50	mA
				IV			75	
$V_{GT}$	$T_j = 25 \text{ }^\circ\text{C}$ Pulse Duration $> 20 \mu\text{s}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III-IV			1.5	V
$V_{GD}$	$T_j = 125 \text{ }^\circ\text{C}$	$V_D = V_{DRM}$	$R_L = 3.3 \text{ k}\Omega$	I-II-III-IV	0.2			V
$I_{H^*}$	$T_j = 25 \text{ }^\circ\text{C}$	$I_T = 100 \text{ mA}$	Gate Open				50	mA
$I_L$	$T_j = 25 \text{ }^\circ\text{C}$ Pulse Duration $> 20 \mu\text{s}$	$V_D = 12 \text{ V}$	$I_G = 150 \text{ mA}$	I-III-IV		50		mA
				II		100		
$V_{TM}^*$	$T_j = 25 \text{ }^\circ\text{C}$	$I_{TM} = 21 \text{ A}$	$t_p = 10 \text{ ms}$				1.5	V
$I_{DRM}^*$	$V_{DRM}$ Specified	$T_j = 25 \text{ }^\circ\text{C}$					0.01	mA
		$T_j = 125 \text{ }^\circ\text{C}$					2	
$dv/dt^*$	$T_j = 125 \text{ }^\circ\text{C}$	Gate Open	Linear Slope up to $V_D = 67\% V_{DRM}$		250	500		V/ $\mu\text{s}$
$(dv/dt)_c^*$	$T_C = 90 \text{ }^\circ\text{C}$ $(di/dt)_c = 6.7 \text{ A/ms}$	$V_D = V_{DRM}$	$I_T = 21 \text{ A}$		10			V/ $\mu\text{s}$
$t_{gl}$	$T_j = 25 \text{ }^\circ\text{C}$	$V_D = V_{DRM}$ $di_G/dt = 3.5 \text{ A}/\mu\text{s}$	$I_T = 21 \text{ A}$	I-II-III-IV		2		$\mu\text{s}$

\* For either polarity of electrode  $A_2$  voltage with reference to electrode  $A_1$ .

**PACKAGE MECHANICAL DATA**

TO 220 AB Plastic



Cooling method : by conduction (method C)

Marking : type number

Weight : 2 g.

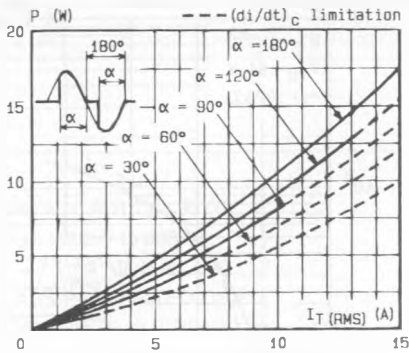


Fig. 1 - Maximum mean power dissipation versus RMS on-state current ( $F = 60 \text{ Hz}$ ).

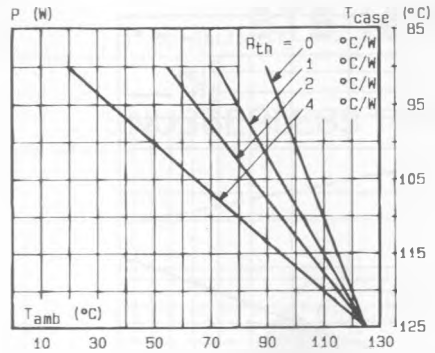


Fig. 2 - Correlation between maximum mean power dissipation and maximum allowable temperatures ( $T_{amb}$  and  $T_{case}$ ) for different thermal resistances heatsink + contact.

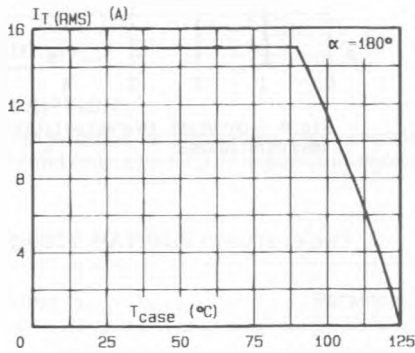


Fig. 3 - RMS on-state current versus case temperature.

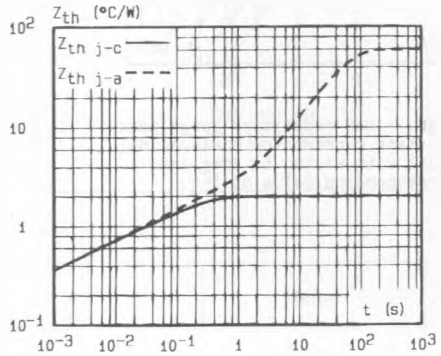


Fig. 4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

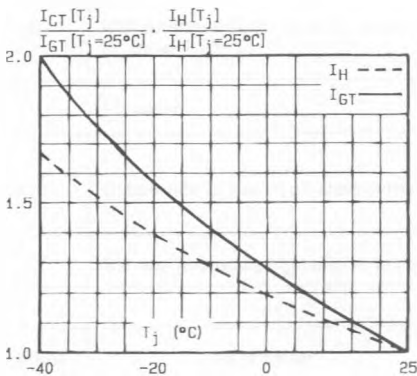


Fig. 5 - Relative variation of gate trigger current and holding current versus junction temperature.

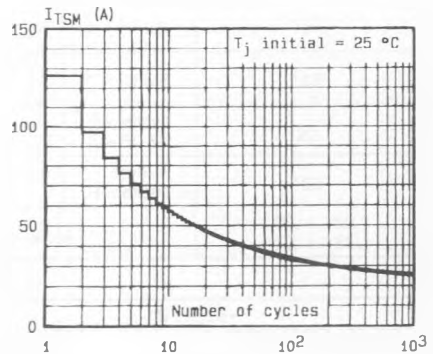


Fig. 6 - Non repetitive surge peak on-state current versus number of cycles.

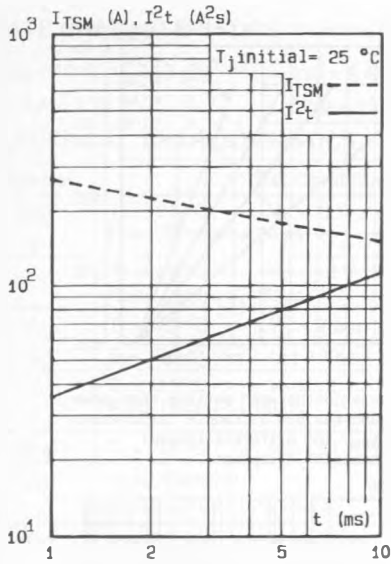


Fig. 7 - Non repetitive surge peak on-state current for a sinusoidal pulse with width:  $t \leq 10\text{ms}$ , and corresponding value of  $I^2t$ .

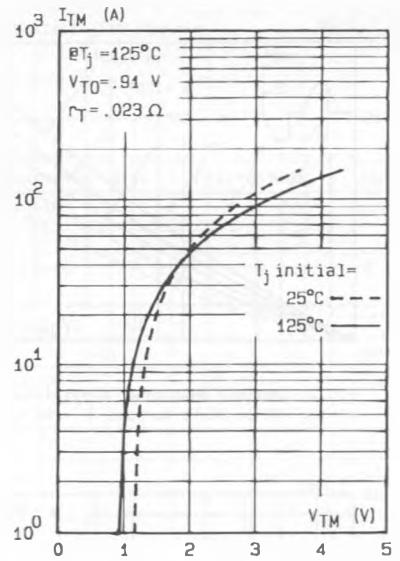


Fig. 8 - On-state characteristic (maximum values).